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**THE OPERATION AND CALIBRATION
OF THE ELECTRON MICROSCOPE**

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*Monographs in Practical Electron Microscopy
in Materials Science*

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THE OPERATION AND CALIBRATION OF THE ELECTRON MICROSCOPE

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PREFACE

This is the first of a series of monographs on electron microscopy aimed at users of the equipment. They are written both as texts and sources of reference emphasising the applications of electron microscopy to the characterisation of materials. The flexible monograph format will enable both the student and the professional scientist to extract the required information easily. In this context the series should be useful in specialist undergraduate and postgraduate lecture courses and as an introduction to the technique for professional scientists.

In some places the author has referred the reader to material appearing in other monographs in this series. The following three monographs are in preparation:

2—*Electron Diffraction in the Electron Microscope*,

3—*Interpretation of Transmission Electron Micrographs* and

4—*Typical Electron Microscope Investigations*.

Subsequent monographs in the series will cover quantitative metallography, together with aspects of design of electron microscopes.

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